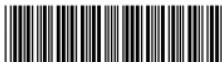


<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10537590	LIU ET AL..
Examiner	Art Unit	
Cehic, Kenan	2616	

### SEARCHED

Class	Subclass	Date	Examiner
370	235,230.1,231,236.1,236.2,389	12/31/2007	KC

### SEARCH NOTES

Search Notes	Date	Examiner
Inventorship Search	12/31/2007	KC
Consulted with SPE Kwang Yao	12/26/2007	KC

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner